

<b>Notice of References Cited</b>	Application/Control No. 09/617,036	Applicant(s)/Patent Under Reexamination PAIK ET AL.	
	Examiner Michael W. Hoye	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE 100: The Authoritative Dictionary of IEEE Standards Terms, 2000, IEEE Press, 7 <sup>th</sup> ed., pages 1158-1159.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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